Search Notes				

Application/Control No.	Applicant(s)/Patent under Reexamination
10/614,207	HOSHINO ET AL.
Fxaminer	Art Unit

1762

Alain L. Bashore

SEARCHED				
Class	Subclass	Date	Examiner	
427	162, 614,165, 166	6/20/2006	ab	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
	<u> </u>		

SEARC (INCLUDING SE	H NOTES ARCH STRATEG	Y)
	DATE	EXMR
EAST (attached)	6/20/2006	АВ
Inventor search	6/20/2006	AB
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